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P10 LTE B26_QPSK15M_Left Cheek_Ch26865_1RB_OS37

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	164.0 x 78.0 x 11.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
LeftHead, -	CHEEK, 0.00	Band 26	LTE-FDD, -	831.500, 26865	9.47	0.918	43.4

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2161	HSL835-2025-02-16	EX3DV4 - SN3873, 2024-09-29	DAE4 Sn1389, 2024-11-11

Scan Setup

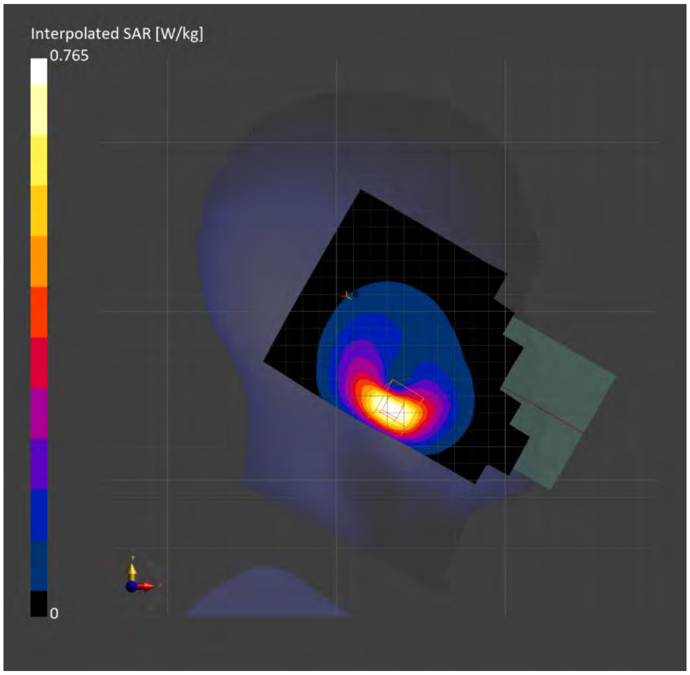
	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-02-16	2025-02-16
psSAR1g [W/kg]	0.623	0.688
psSAR10g [W/kg]	0.382	0.358
Power Drift [dB]	0.07	0.01
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		76.1
Dist 3dB Peak [mm]		7.8

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



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P11 LTE B38_QPSK20M_Right Tilted_Ch37850_50RB_OS25

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	164.0 x 78.0 x 11.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
RightHead, -	TILT, 0.00	Band 38	LTE-TDD, -	2580.000, 37850	7.31	1.93	37.7

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2161	HSL2550-2025-03-04	EX3DV4 - SN3873, 2024-09-29	DAE4 Sn1389, 2024-11-11

Scan Setup

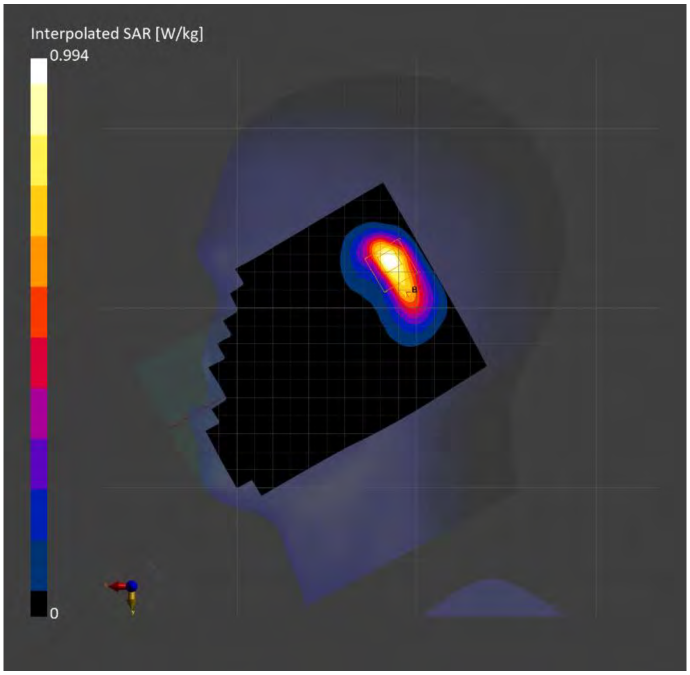
	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 200.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 5.0
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-03-04	2025-03-04
psSAR1g [W/kg]	0.735	0.799
psSAR10g [W/kg]	0.329	0.321
Power Drift [dB]	-0.09	-0.09
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		44.6
Dist 3dB Peak [mm]		6.1

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



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P12 LTE B41_QPSK20M_Right Tilted_Ch39750_1RB_OS0

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	164.0 x 78.0 x 11.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
RightHead, -	TILT, 0.00	Band 41	LTE-TDD, -	2506.000, 39750	7.31	1.88	37.8

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2135	HSL2550-2025-02-25	EX3DV4 - SN3873, 2024-09-29	DAE4 Sn1389, 2024-11-11

Scan Setup

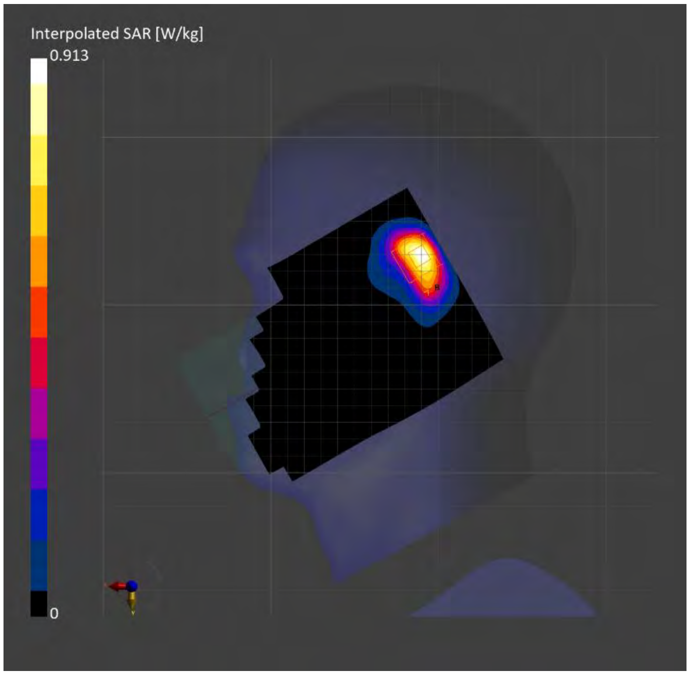
	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 200.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-02-25	2025-02-25
psSAR1g [W/kg]	0.676	0.772
psSAR10g [W/kg]	0.324	0.323
Power Drift [dB]	0.01	0.02
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		75.8
Dist 3dB Peak [mm]		6.4

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



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P13 LTE B42_QPSK20M_Right Cheek_Ch43190_1RB_OS50

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	164.0 x 78.0 x 11.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
RightHead, -	CHEEK, 0.00	Band 42	LTE-TDD, -	3560.000, 43190	6.71	2.89	37.1

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2161	HSL3500-2025-02-23	EX3DV4 - SN3873, 2024-09-29	DAE4 Sn1389, 2024-11-11

Scan Setup

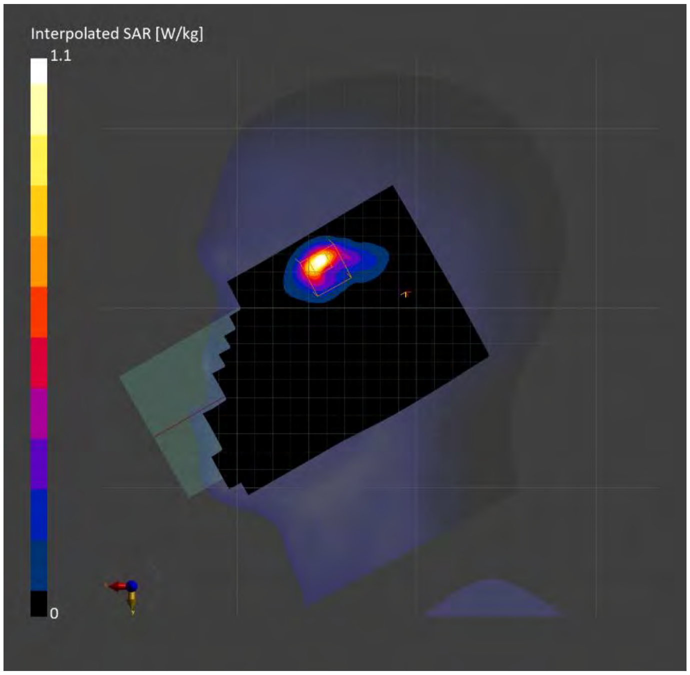
	Area Scan	Zoom Scan
Grid Extents [mm]	112.0 x 208.0	28.0 x 28.0 x 28.0
Grid Steps [mm]	8.0 x 8.0	5.0 x 5.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.4
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-02-23	2025-02-23
psSAR1g [W/kg]	0.670	0.679
psSAR10g [W/kg]	0.236	0.224
Power Drift [dB]	0.10	0.08
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		69.8
Dist 3dB Peak [mm]		4.6

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



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P14 LTE B48_QPSK20M_Right Tilted_Ch56150_1RB_OS50

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	164.0 x 78.0 x 10.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
RightHead, -	TILT, 0.00	Band 48	LTE-TDD, -	3641.000, 56150	6.71	2.96	36.9

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2135	HSL3500-2025-02-23	EX3DV4 - SN3873, 2024-09-29	DAE4 Sn1389, 2024-11-11

Scan Setup

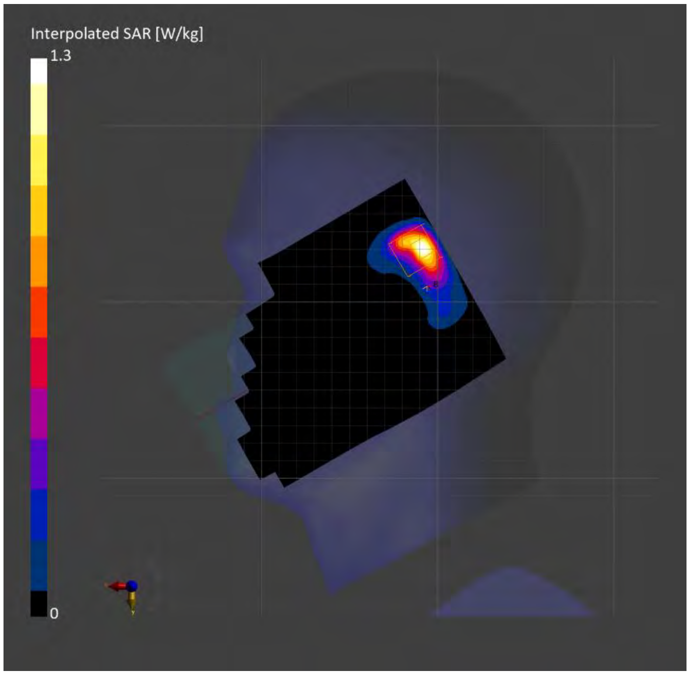
	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 200.0	28.0 x 28.0 x 28.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-02-23	2025-02-23
psSAR1g [W/kg]	0.848	0.825
psSAR10g [W/kg]	0.319	0.290
Power Drift [dB]	0.10	-0.02
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		72.5
Dist 3dB Peak [mm]		5.8

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



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P15 LTE B66_QPSK20M_Right Cheek_Ch132322_1RB_OS50

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	164.0 x 78.0 x 11.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
RightHead, -	CHEEK, 0.00	Band 66	LTE-FDD, -	1745.000, 132322	8.31	1.40	39.2

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2161	HSL1750-2025-02-20	EX3DV4 - SN3873, 2024-09-29	DAE4 Sn1389, 2024-11-11

Scan Setup

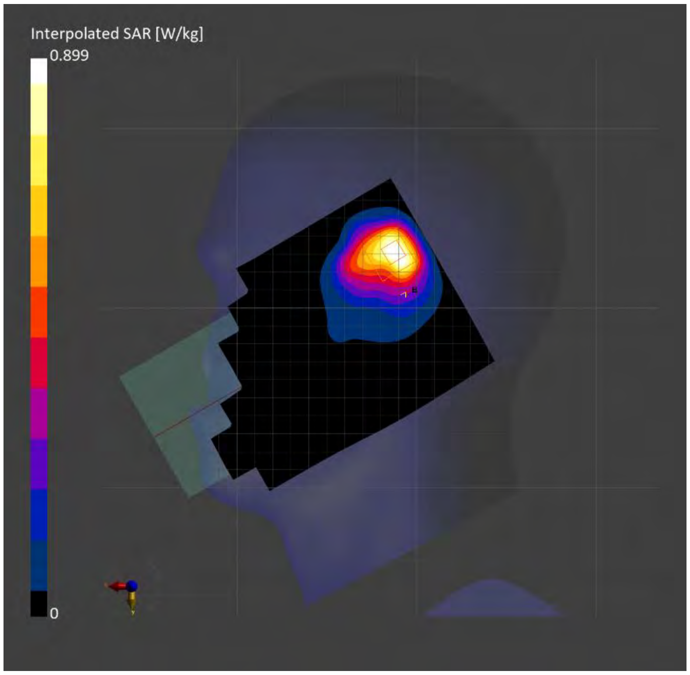
	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-02-20	2025-02-20
psSAR1g [W/kg]	0.727	0.836
psSAR10g [W/kg]	0.402	0.406
Power Drift [dB]	-0.01	-0.01
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		81.8
Dist 3dB Peak [mm]		7.3

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



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P16 FR N2_DFT-QPSK40M_Right Cheek_Ch374000_108RB_OS54

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	164.0 x 78.0 x 11.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
RightHead, -	CHEEK, 0.00	Band n2	5G NR FR1 FDD, -	1870.000, 374000	7.97	1.38	40.8

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2161	HSL1950-2025-02-21	EX3DV4 - SN3873, 2024-09-29	DAE4 Sn1389, 2024-11-11

Scan Setup

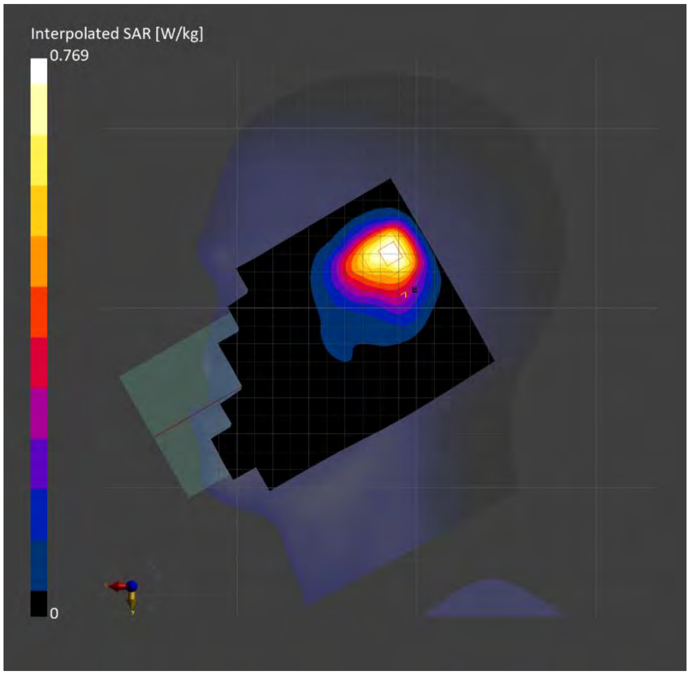
	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-02-21	2025-02-21
psSAR1g [W/kg]	0.616	0.698
psSAR10g [W/kg]	0.350	0.359
Power Drift [dB]	0.05	-0.05
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		83.2
Dist 3dB Peak [mm]		7.3

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



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P17 FR N5_DFT-QPSK20M_Left Cheek_Ch167300_1RB_OS1

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	164.0 x 78.0 x 11.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
LeftHead, -	CHEEK, 0.00	Band n5	5G NR FR1 FDD, -	836.500, 167300	9.47	0.942	43.3

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2161	HSL835-2025-02-18	EX3DV4 - SN3873, 2024-09-29	DAE4 Sn1389, 2024-11-11

Scan Setup

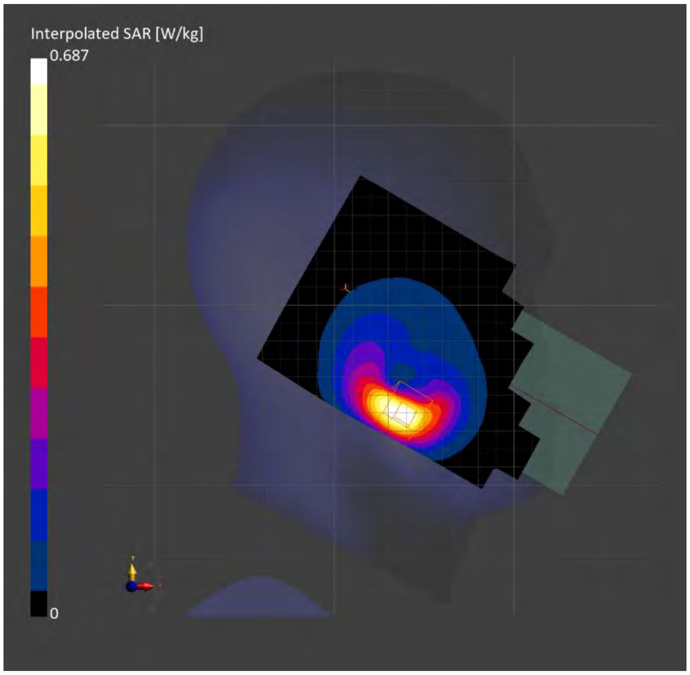
	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-02-18	2025-02-18
psSAR1g [W/kg]	0.563	0.592
psSAR10g [W/kg]	0.340	0.320
Power Drift [dB]	0.07	-0.00
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		79.4
Dist 3dB Peak [mm]		7.7

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



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P18 FR N7_DFT-QPSK50M_Right Tilted_Ch509000_1RB_OS1

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	164.0 x 78.0 x 11.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
RightHead, -	TILT, 0.00	Band n7	5G NR FR1 FDD, -	2545.000, 509000	7.31	1.90	37.9

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2161	HSL2550-2025-02-22	EX3DV4 - SN3873, 2024-09-29	DAE4 Sn1389, 2024-11-11

Scan Setup

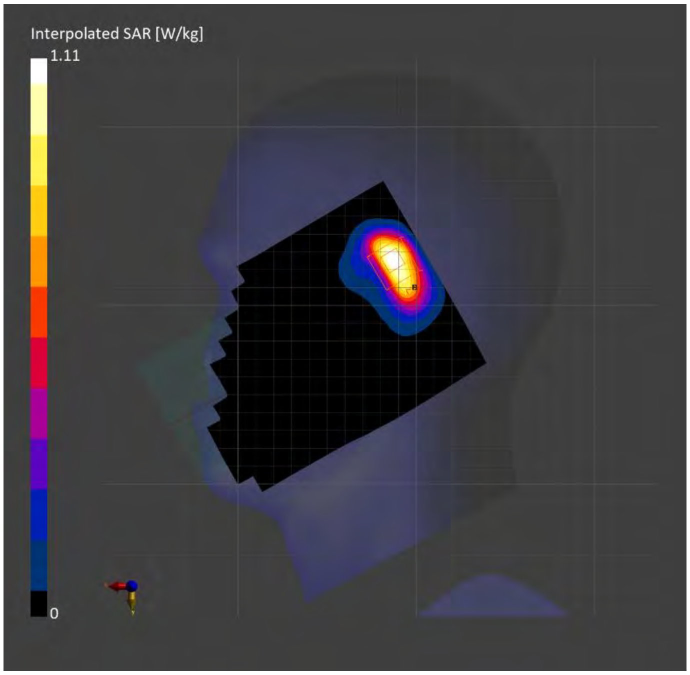
	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 200.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 5.0
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-02-22	2025-02-22
psSAR1g [W/kg]	0.849	0.962
psSAR10g [W/kg]	0.405	0.408
Power Drift [dB]	-0.01	-0.01
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		41.1
Dist 3dB Peak [mm]		6.1

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



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P19 FR N38_DFT-QPSK40M_Left Cheek_Ch519000_50RB_OS28

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	164.0 x 78.0 x 11.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
LeftHead, -	CHEEK, 0.00	Band n38	5G NR FR1 TDD, -	2595.000, 519000	7.31	1.94	37.7

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2135	HSL2550-2025-03-04	EX3DV4 - SN3873, 2024-09-29	DAE4 Sn1389, 2024-11-11

Scan Setup

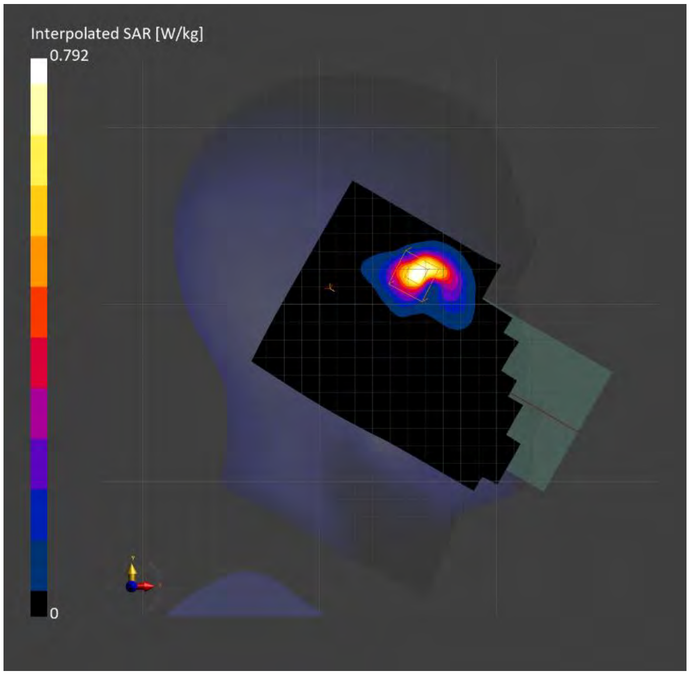
	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 200.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-03-04	2025-03-04
psSAR1g [W/kg]	0.574	0.582
psSAR10g [W/kg]	0.244	0.238
Power Drift [dB]	-0.12	0.03
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		74.4
Dist 3dB Peak [mm]		6.5

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



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P20 FR N41_DFT-QPSK100M_Right Cheek_Ch509202_135RB_OS69

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	164.0 x 78.0 x 11.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
RightHead, -	CHEEK, 0.00	Band n41	5G NR FR1 TDD, -	2546.010, 509202	7.31	1.90	37.8

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2161	HSL2550-2025-02-25	EX3DV4 - SN3873, 2024-09-29	DAE4 Sn1389, 2024-11-11

Scan Setup

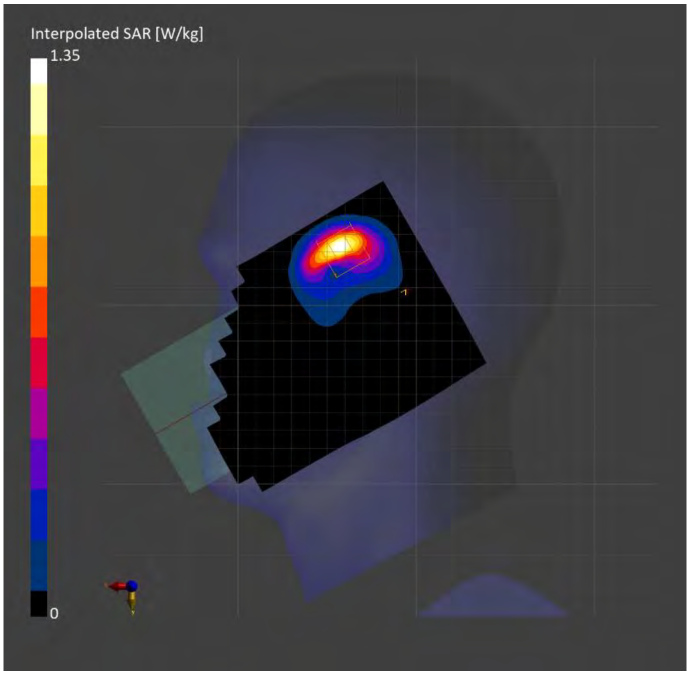
	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 200.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-02-25	2025-02-25
psSAR1g [W/kg]	0.939	0.820
psSAR10g [W/kg]	0.404	0.383
Power Drift [dB]	-0.01	0.01
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		78.5
Dist 3dB Peak [mm]		6.7

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



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P21 FR N48_DFT-QPSK40M_Right Cheek_Ch645332_50RB_OS28

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	164.0 x 78.0 x 11.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
RightHead, -	CHEEK, 0.00	Band n48	5G NR FR1 TDD, -	3679.975, 645332	6.71	2.99	36.9

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2161	HSL3500-2025-02-23	EX3DV4 - SN3873, 2024-09-29	DAE4 Sn1389, 2024-11-11

Scan Setup

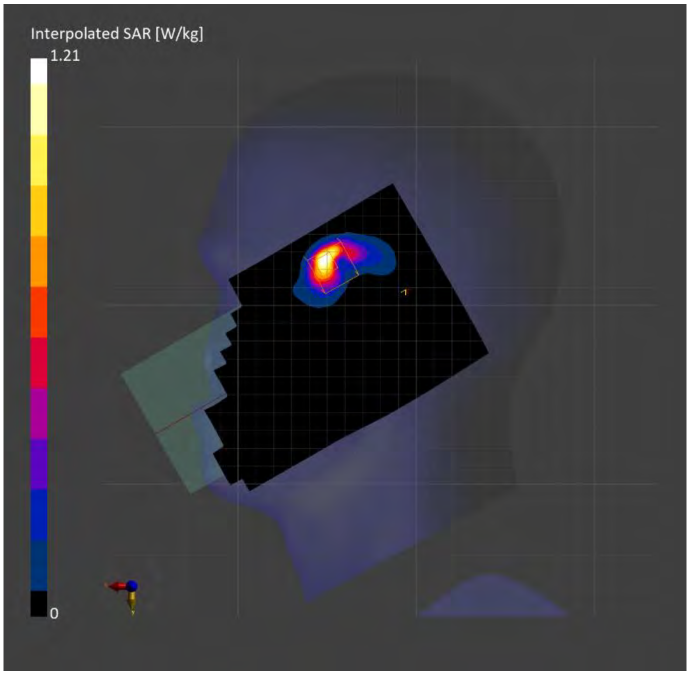
	Area Scan	Zoom Scan
Grid Extents [mm]	112.0 x 208.0	28.0 x 28.0 x 28.0
Grid Steps [mm]	8.0 x 8.0	5.0 x 5.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.4
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-02-23	2025-02-23
psSAR1g [W/kg]	0.749	0.764
psSAR10g [W/kg]	0.259	0.252
Power Drift [dB]	0.06	0.04
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		70.3
Dist 3dB Peak [mm]		4.3

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



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P22 FR N66_DFT-QPSK45M_Right Cheek_Ch351500_1RB_OS1

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	164.0 x 78.0 x 11.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
RightHead, -	CHEEK, 0.00	Band n66	5G NR FR1 FDD, -	1757.500, 351500	8.31	1.41	39.2

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2161	HSL1750-2025-02-20	EX3DV4 - SN3873, 2024-09-29	DAE4 Sn1389, 2024-11-11

Scan Setup

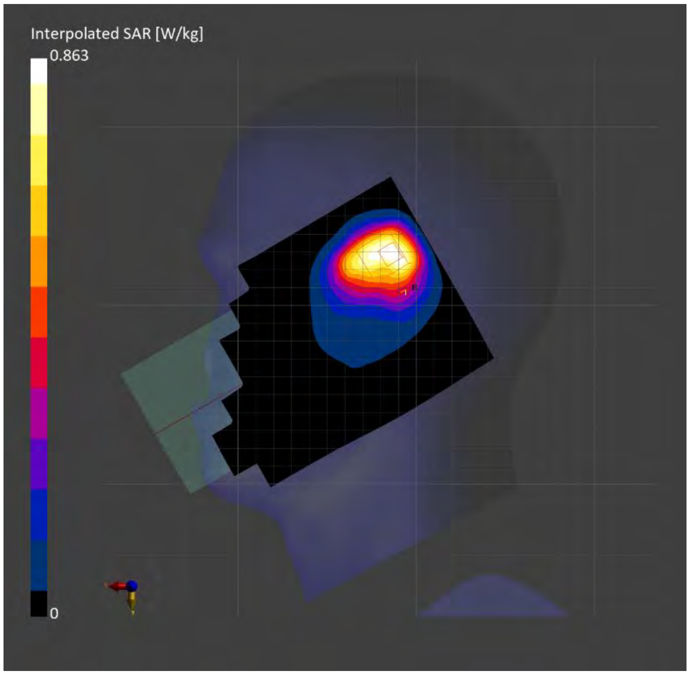
	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-02-20	2025-02-20
psSAR1g [W/kg]	0.702	0.842
psSAR10g [W/kg]	0.412	0.435
Power Drift [dB]	0.02	0.02
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		81.7
Dist 3dB Peak [mm]		7.3

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



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P23 FR N77_DFT-QPSK100M_Right Cheek_Ch633334_135RB_OS69

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	164.0 x 78.0 x 11.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
RightHead, -	CHEEK, 0.00	Band n77	5G NR FR1 TDD, -	3500.010, 633334	6.71	2.79	39.4

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2161	HSL3500-2025-03-06	EX3DV4 - SN3873, 2024-09-29	DAE4 Sn1389, 2024-11-11

Scan Setup

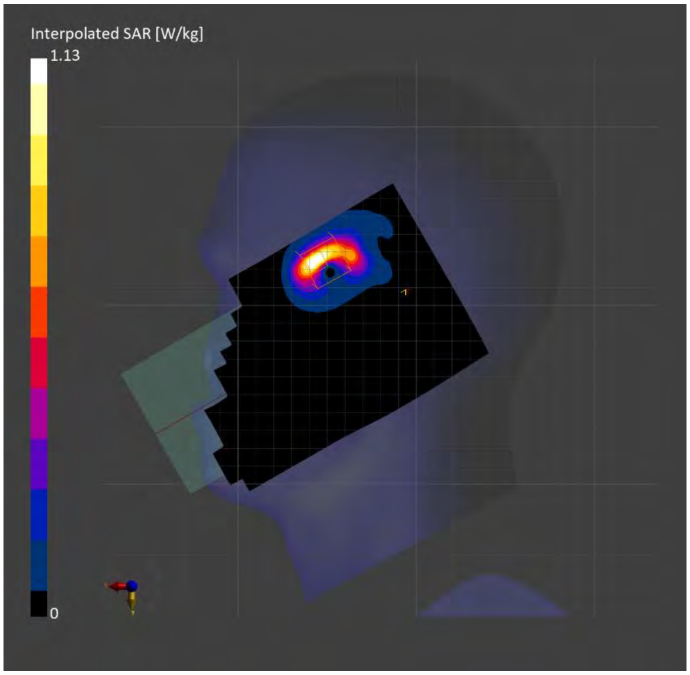
	Area Scan	Zoom Scan
Grid Extents [mm]	112.0 x 208.0	28.0 x 28.0 x 28.0
Grid Steps [mm]	8.0 x 8.0	5.0 x 5.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.2
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-03-06	2025-03-06
psSAR1g [W/kg]	0.695	0.738
psSAR10g [W/kg]	0.250	0.251
Power Drift [dB]	-0.06	0.04
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		76.8
Dist 3dB Peak [mm]		4.2

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



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P24 FR N78_DFT-QPSK100M_Right Tilted_Ch633334_1RB_OS1

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	164.0 x 78.0 x 11.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
RightHead, -	TILT, 0.00	Band n78	5G NR FR1 TDD, -	3500.010, 633334	6.71	2.83	39.0

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2161	HSL3500-2025-03-09	EX3DV4 - SN3873, 2024-09-29	DAE4 Sn1389, 2024-11-11

Scan Setup

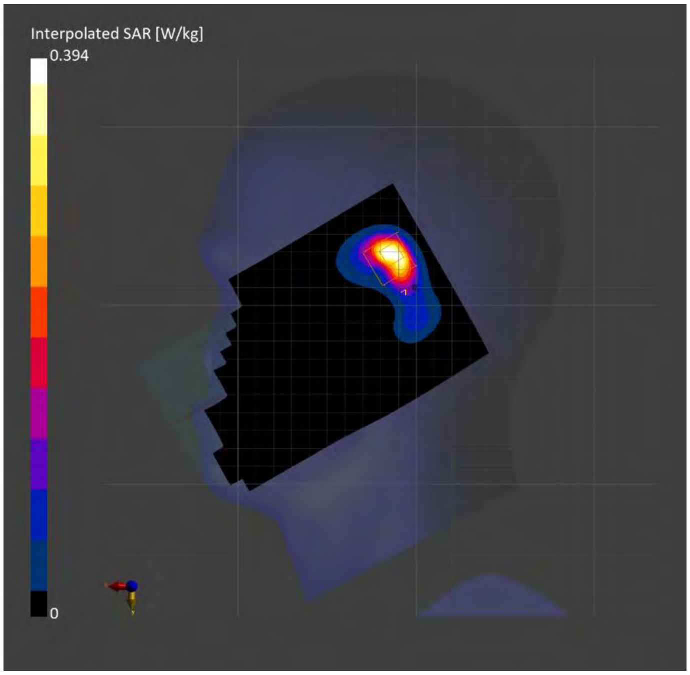
	Area Scan	Zoom Scan
Grid Extents [mm]	112.0 x 208.0	24.0 x 24.0 x 22.0
Grid Steps [mm]	8.0 x 8.0	4.0 x 4.0 x 2.0
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	Y	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-03-09	2025-03-09
psSAR1g [W/kg]	0.274	0.296
psSAR10g [W/kg]	0.106	0.106
Power Drift [dB]	-0.00	0.02
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		64.7
Dist 3dB Peak [mm]		5.4

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



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P25 WLAN2.4G_802.11ax HE20_Left Cheek_Ch6

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	164.0 x 78.0 x 11.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
LeftHead, -	CHEEK, 0.00	WLAN 2.4GHz	WLAN, -	2437.000, 6	7.46	1.72	40.0

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2161	HSL2450-2025-02-27	EX3DV4 - SN3873, 2024-09-29	DAE4 Sn1389, 2024-11-11

Scan Setup

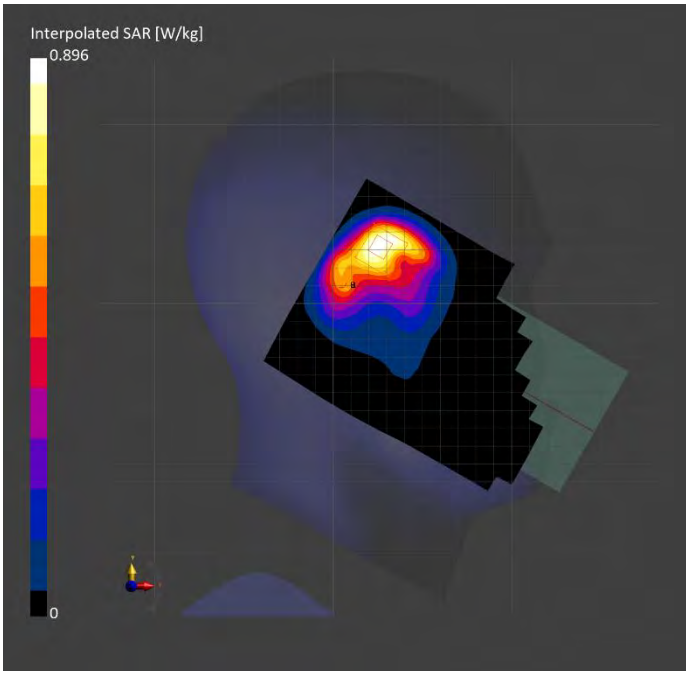
	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 200.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-02-27	2025-02-27
psSAR1g [W/kg]	0.706	0.726
psSAR10g [W/kg]	0.379	0.378
Power Drift [dB]	-0.03	-0.00
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		87.6
Dist 3dB Peak [mm]		10.8

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



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P26 WLAN5.2G_802.11ax HE20_Left Tilted_Ch60

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	164.0 x 78.0 x 11.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
LeftHead, -	TILT, 0.00	WLAN 5GHz	WLAN, -	5300.000, 60	5.16	4.71	35.5

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2161	HSL5G-2025-03-11	EX3DV4 - SN3873, 2024-09-29	DAE4 Sn1389, 2024-11-11

Scan Setup

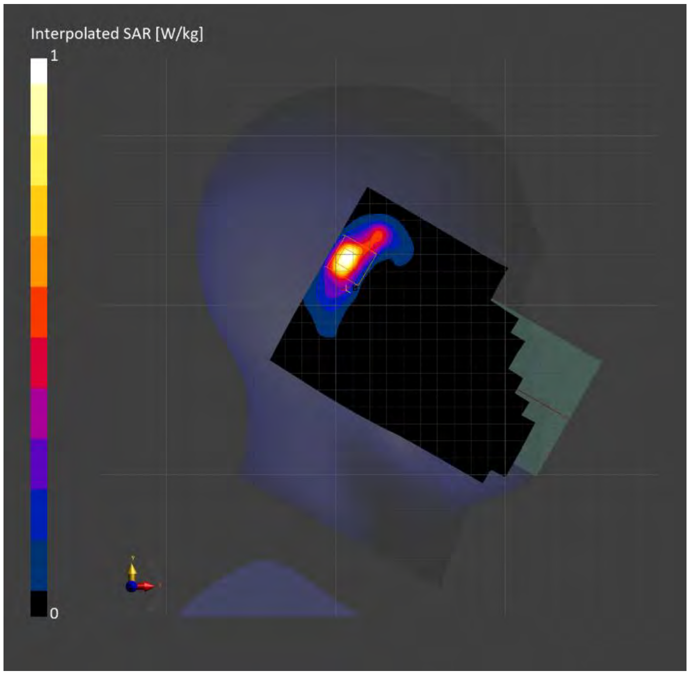
	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 200.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.4
MAIA	Y	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-03-11	2025-03-11
psSAR1g [W/kg]	0.674	0.876
psSAR10g [W/kg]	0.222	0.226
Power Drift [dB]	0.15	-0.06
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		64.6
Dist 3dB Peak [mm]		4.6

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



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P27 WLAN5.5G_802.11n HT20_Left Cheek_Ch144

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	164.0 x 78.0 x 11.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
LeftHead, -	CHEEK, 0.00	WLAN 5GHz	WLAN, -	5720.000, 144	5.16	5.17	34.8

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2161	HSL5G-2025-03-12	EX3DV4 - SN3873, 2024-09-29	DAE4 Sn1389, 2024-11-11

Scan Setup

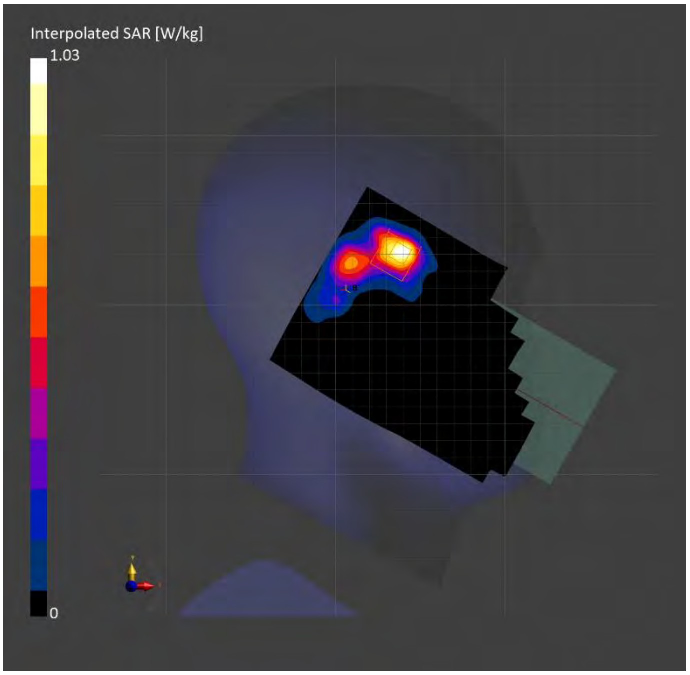
	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 200.0	24.0 x 24.0 x 22.0
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 2.0
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.4
MAIA	Y	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-03-12	2025-03-12
psSAR1g [W/kg]	0.709	0.666
psSAR10g [W/kg]	0.252	0.233
Power Drift [dB]	-0.04	-0.04
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		45.1
Dist 3dB Peak [mm]		6.5

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



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P28 WLAN5.8G_802.11be HE20_Left Tilted_Ch157

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	164.0 x 78.0 x 11.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
LeftHead, -	TILT, 0.00	WLAN 5GHz	WLAN, -	5785.000, 157	5.16	5.14	35.1

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2161	HSL5G-2025-03-13	EX3DV4 - SN3873, 2024-09-29	DAE4 Sn1389, 2024-11-11

Scan Setup

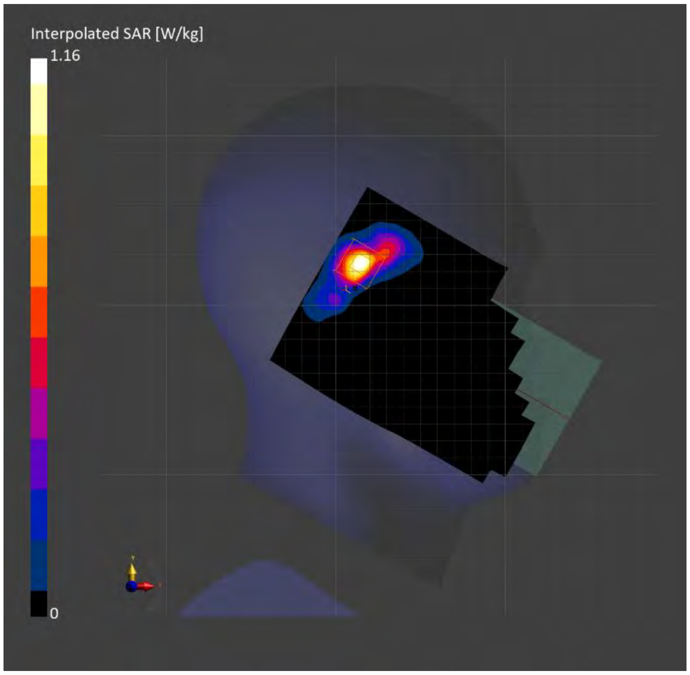
	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 200.0	24.0 x 24.0 x 22.0
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 2.0
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.4
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-03-13	2025-03-13
psSAR1g [W/kg]	0.784	0.796
psSAR10g [W/kg]	0.252	0.260
Power Drift [dB]	0.01	0.16
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		51.1
Dist 3dB Peak [mm]		5.1

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



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P29 BT_GFSK_Left Cheek_Ch0

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	164.0 x 78.0 x 11.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
LeftHead, -	CHEEK, 0.00	ISM 2.4 GHz Band	Bluetooth, -	2402.000, 0	7.46	1.72	40.0

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2135	HSL2450-2025-02-27	EX3DV4 - SN3873, 2024-09-29	DAE4 Sn1389, 2024-11-11

Scan Setup

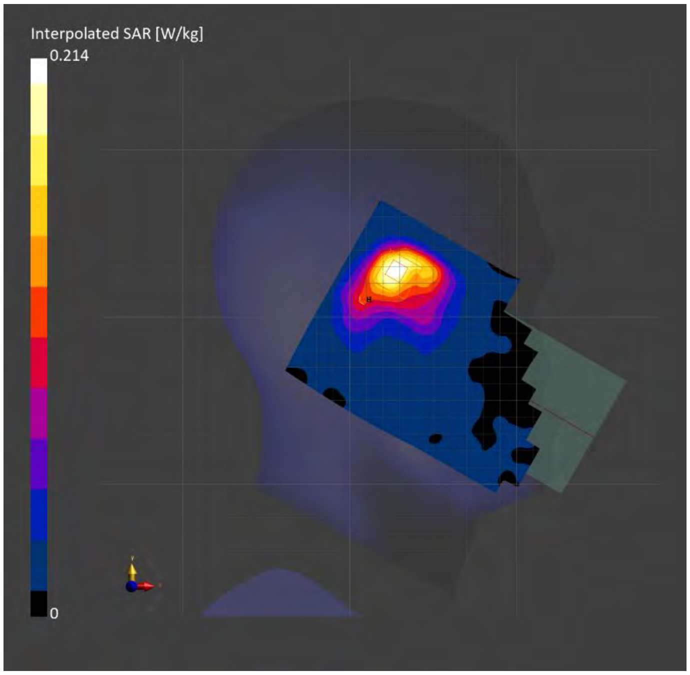
	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 200.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	Y	Y
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-02-27	2025-02-27
psSAR1g [W/kg]	0.168	0.136
psSAR10g [W/kg]	0.088	0.081
Power Drift [dB]	-0.05	-0.06
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		79.6
Dist 3dB Peak [mm]		7.4

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



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P30 GSM850_GPRS 3Tx Slot_Rear Face_1.5cm_Ch189

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	164.0 x 78.0 x 11.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	BACK, 15.00	GSM 850	GSM, -	836.400, 189	9.47	0.920	43.4

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2161	HSL835-2025-02-16	EX3DV4 - SN3873, 2024-09-29	DAE4 Sn1389, 2024-11-11

Scan Setup

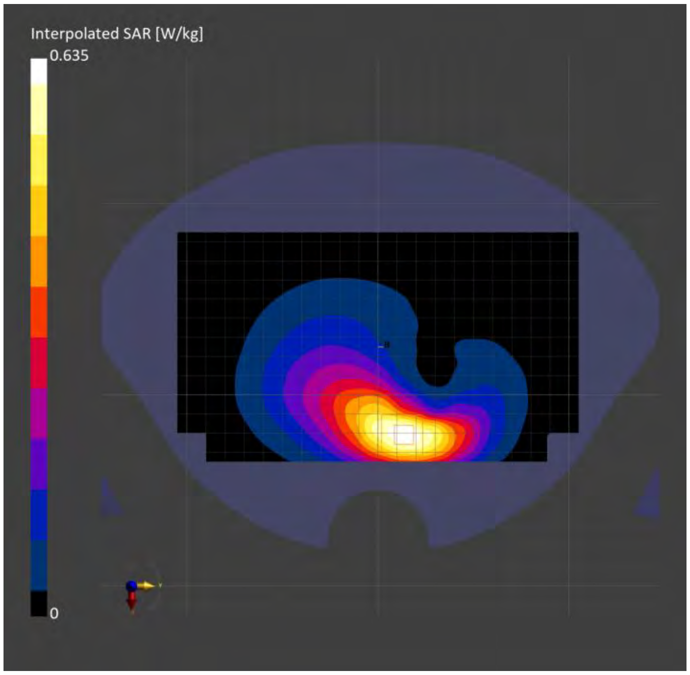
	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-02-16	2025-02-16
psSAR1g [W/kg]	0.542	0.535
psSAR10g [W/kg]	0.347	0.340
Power Drift [dB]	-0.14	-0.01
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		83.7
Dist 3dB Peak [mm]		12.6

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



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P31 GSM1900_GPRS 2Tx Slot_Front Face_1.5cm_Ch661

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	164.0 x 78.0 x 11.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	FRONT, 15.00	PCS 1900	GSM, -	1880.000, 661	7.97	1.38	40.8

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2161	HSL1950-2025-02-26	EX3DV4 - SN3873, 2024-09-29	DAE4 Sn1389, 2024-11-11

Scan Setup

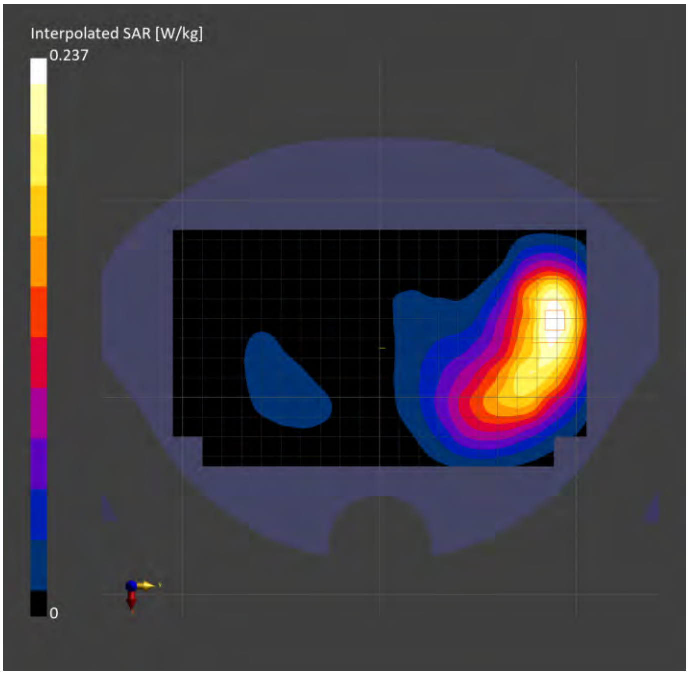
	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-02-26	2025-02-26
psSAR1g [W/kg]	0.194	0.195
psSAR10g [W/kg]	0.116	0.116
Power Drift [dB]	0.00	0.04
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		83.9
Dist 3dB Peak [mm]		13.2

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



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P32 WCDMA II_RMC12.2K_Rear Face_1.5cm_Ch9262

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	164.0 x 78.0 x 11.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	BACK, 15.00	Band 2	WCDMA, -	1852.400, 9262	7.97	1.36	40.8

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2161	HSL1950-2025-02-26	EX3DV4 - SN3873, 2024-09-29	DAE4 Sn1389, 2024-11-11

Scan Setup

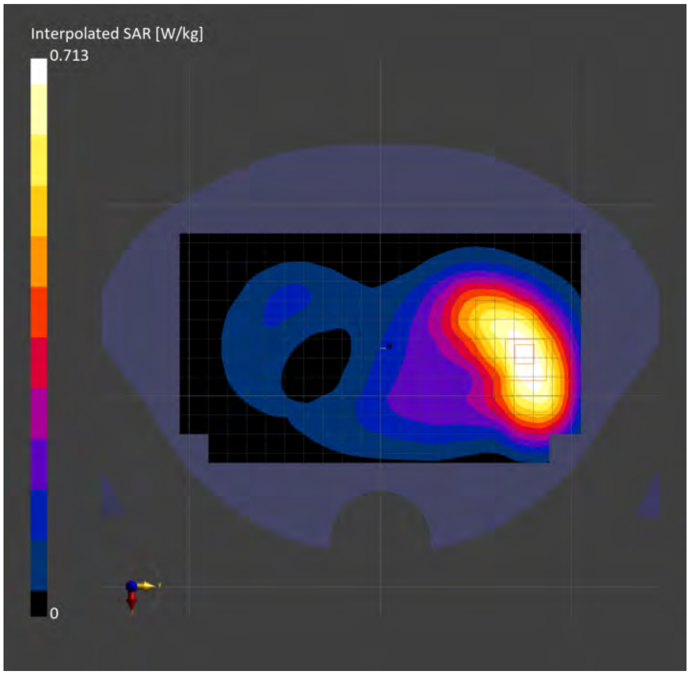
	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-02-26	2025-02-26
psSAR1g [W/kg]	0.596	0.624
psSAR10g [W/kg]	0.364	0.392
Power Drift [dB]	-0.02	0.02
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		85.2
Dist 3dB Peak [mm]		18.8

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



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P33 WCDMA IV_RMC12.2K_Rear Face_1.5cm_Ch1413

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	164.0 x 78.0 x 11.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	BACK, 15.00	Band 4	WCDMA, -	1732.600, 1413	8.31	1.33	41.5

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2161	HSL1750-2025-02-17	EX3DV4 - SN3873, 2024-09-29	DAE4 Sn1389, 2024-11-11

Scan Setup

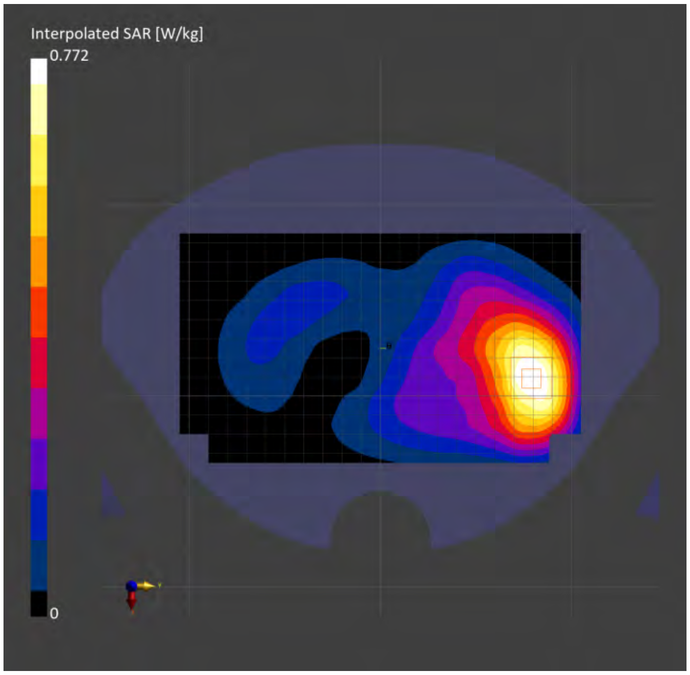
	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-02-17	2025-02-17
psSAR1g [W/kg]	0.658	0.799
psSAR10g [W/kg]	0.407	0.439
Power Drift [dB]	0.02	-0.05
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		86.1
Dist 3dB Peak [mm]		17.8

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



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P34 WCDMA V_RMC12.2K_Rear Face_1.5cm_Ch4132

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	164.0 x 78.0 x 11.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	BACK, 15.00	Band 5	WCDMA, -	826.400, 4132	9.47	0.938	43.3

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2161	HSL835-2025-02-18	EX3DV4 - SN3873, 2024-09-29	DAE4 Sn1389, 2024-11-11

Scan Setup

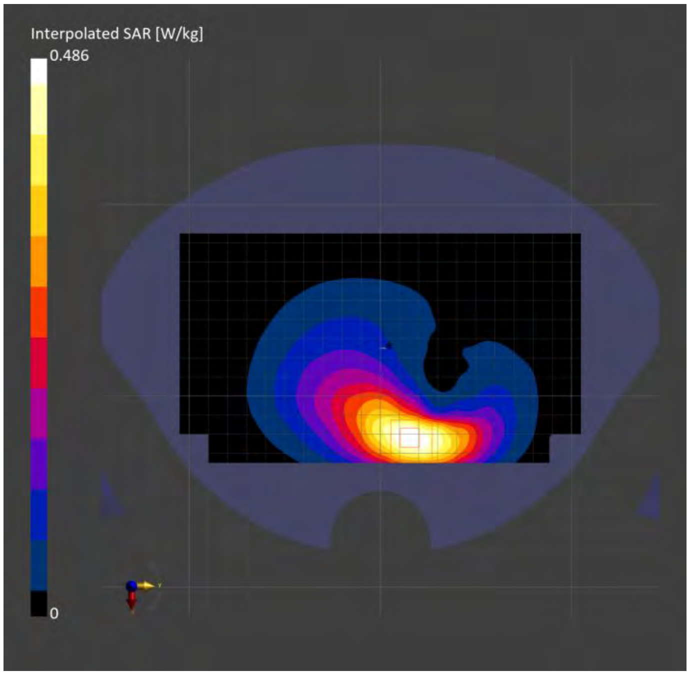
	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-02-18	2025-02-18
psSAR1g [W/kg]	0.419	0.430
psSAR10g [W/kg]	0.268	0.272
Power Drift [dB]	-0.01	-0.03
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		82.5
Dist 3dB Peak [mm]		12.6

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



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P35 LTE B2_QPSK20M_Rear Face_1.5cm_Ch19100_1RB_OS50

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	164.0 x 78.0 x 11.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	BACK, 15.00	Band 2	LTE-FDD, -	1900.000, 19100	7.97	1.40	40.8

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2161	HSL1950-2025-02-21	EX3DV4 - SN3873, 2024-09-29	DAE4 Sn1389, 2024-11-11

Scan Setup

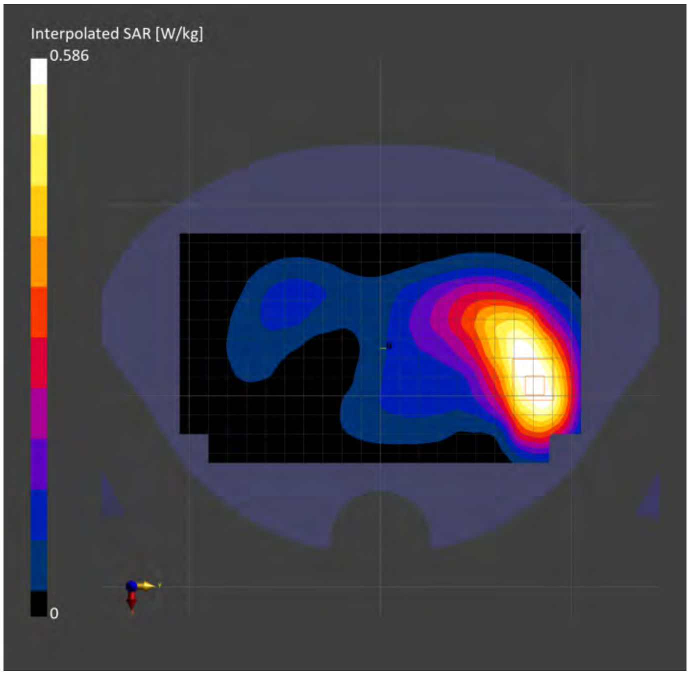
	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-02-21	2025-02-21
psSAR1g [W/kg]	0.494	0.520
psSAR10g [W/kg]	0.303	0.320
Power Drift [dB]	0.01	-0.04
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		85.4
Dist 3dB Peak [mm]		17.1

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



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P36 LTE B4_QPSK20M_Front Face_1.5cm_Ch20050_1RB_OS50

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	164.0 x 78.0 x 11.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	FRONT, 15.00	Band 4	LTE-FDD, -	1720.000, 20050	8.31	1.32	41.5

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2161	HSL1750-2025-02-17	EX3DV4 - SN3873, 2024-09-29	DAE4 Sn1389, 2024-11-11

Scan Setup

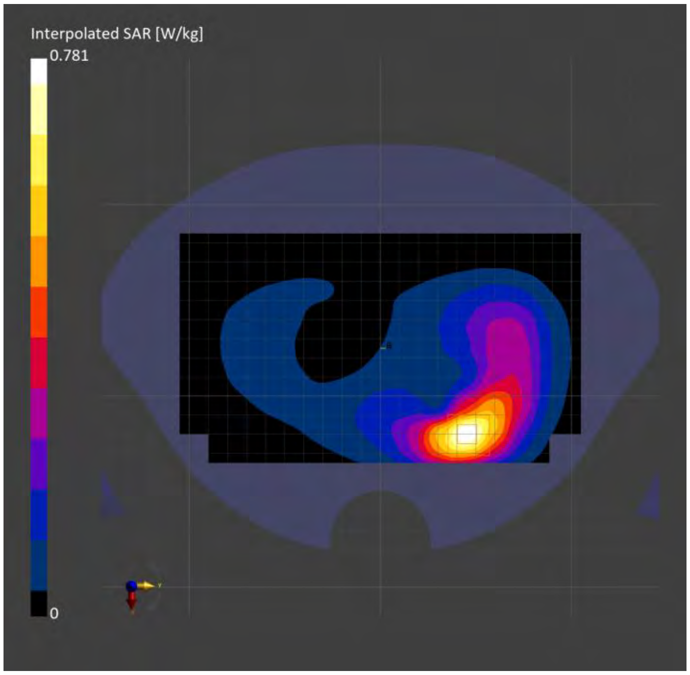
	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-02-17	2025-02-17
psSAR1g [W/kg]	0.625	0.645
psSAR10g [W/kg]	0.350	0.365
Power Drift [dB]	-0.02	0.01
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		83.3
Dist 3dB Peak [mm]		11.1

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



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P37 LTE B7_QPSK20M_Rear Face_1.5cm_Ch21100_1RB_OS0

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	164.0 x 78.0 x 11.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	BACK, 15.00	Band 7	LTE-FDD, -	2535.000, 21100	7.31	1.90	37.9

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2161	HSL2550-2025-02-22	EX3DV4 - SN3873, 2024-09-29	DAE4 Sn1389, 2024-11-11

Scan Setup

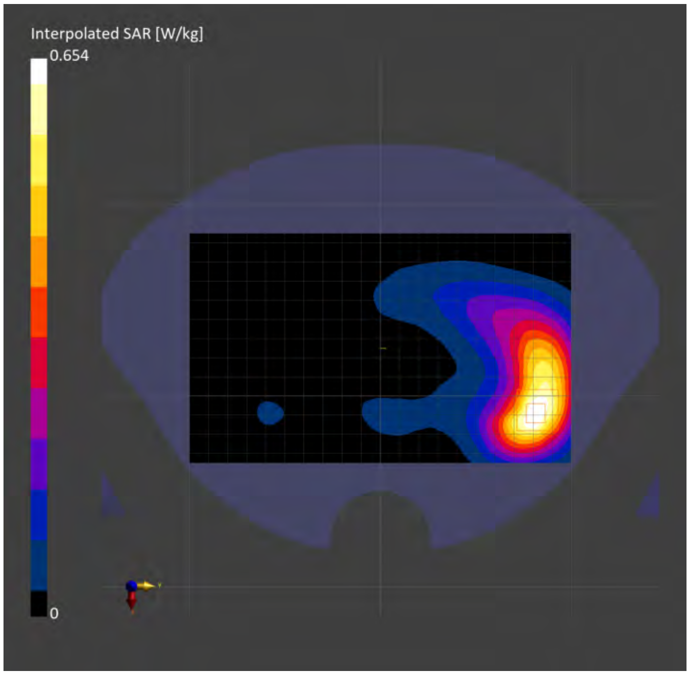
	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 200.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-02-22	2025-02-22
psSAR1g [W/kg]	0.524	0.533
psSAR10g [W/kg]	0.279	0.283
Power Drift [dB]	-0.04	0.04
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		80.9
Dist 3dB Peak [mm]		13.7

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



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P38 LTE B26_QPSK15M_Rear Face_1.5cm_Ch26865_36RB_OS19

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	164.0 x 78.0 x 11.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	BACK, 15.00	Band 26	LTE-FDD, -	831.500, 26865	9.47	0.918	43.4

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2161	HSL835-2025-02-16	EX3DV4 - SN3873, 2024-09-29	DAE4 Sn1389, 2024-11-11

Scan Setup

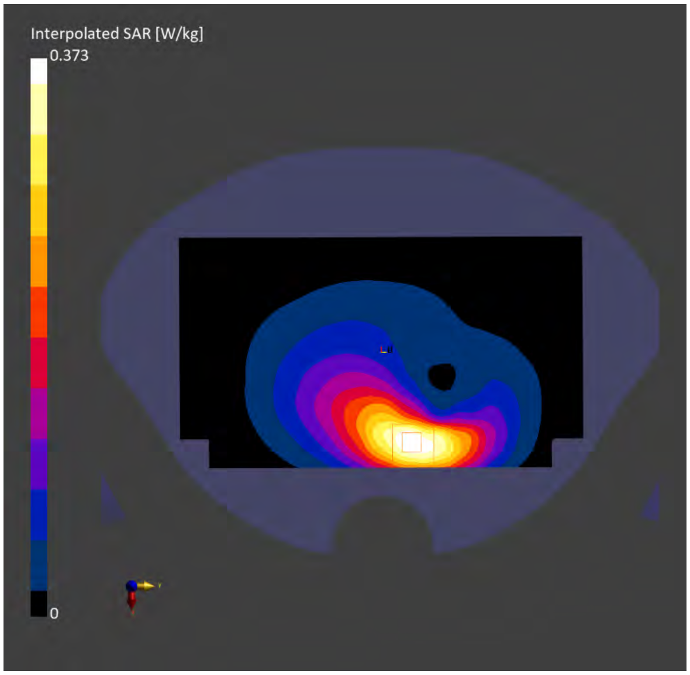
	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-02-16	2025-02-16
psSAR1g [W/kg]	0.322	0.328
psSAR10g [W/kg]	0.207	0.208
Power Drift [dB]	-0.01	0.05
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		82.8
Dist 3dB Peak [mm]		13.0

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



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P39 LTE B38_QPSK20M_Rear Face_1.5cm_Ch38000_1RB_OS0

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	164.0 x 78.0 x 11.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	BACK, 15.00	Band 38	LTE-TDD, -	2595.000, 38000	7.31	1.94	37.7

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2161	HSL2550-2025-03-04	EX3DV4 - SN3873, 2024-09-29	DAE4 Sn1389, 2024-11-11

Scan Setup

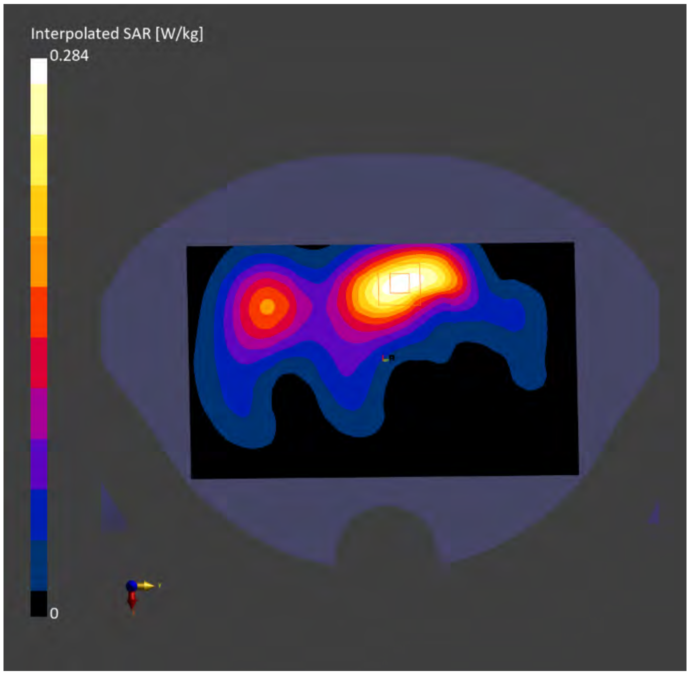
	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 200.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-03-04	2025-03-04
psSAR1g [W/kg]	0.226	0.230
psSAR10g [W/kg]	0.121	0.125
Power Drift [dB]	0.03	-0.02
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		81.7
Dist 3dB Peak [mm]		14.4

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



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P40 LTE B41_QPSK20M_Rear Face_1.5cm_CH39750_1RB_OS0

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	164.0 x 78.0 x 11.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	BACK, 15.00	Band 41	LTE-TDD, -	2506.000, 39750	7.31	1.88	37.8

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2161	HSL2550-2025-02-25	EX3DV4 - SN3873, 2024-09-29	DAE4 Sn1389, 2024-11-11

Scan Setup

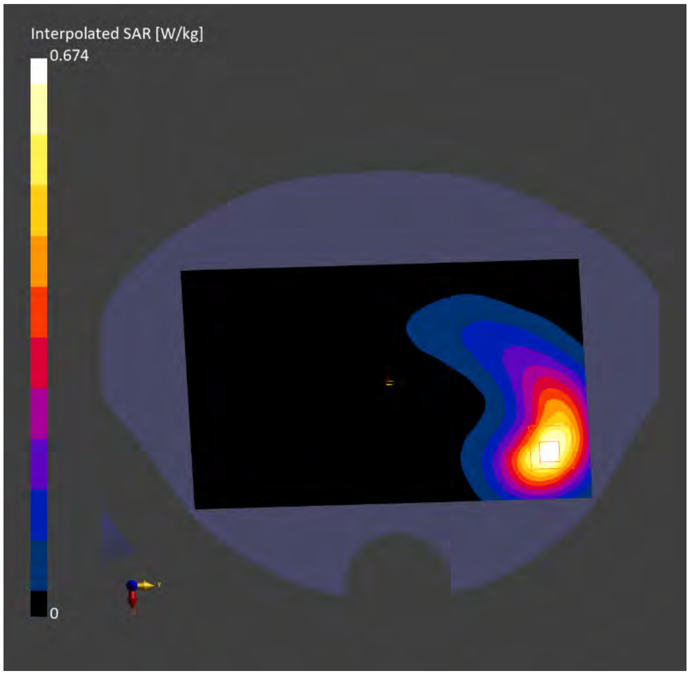
	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 200.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-02-25	2025-02-25
psSAR1g [W/kg]	0.535	0.541
psSAR10g [W/kg]	0.281	0.285
Power Drift [dB]	0.02	-0.01
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		81.5
Dist 3dB Peak [mm]		13.5

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



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P41 LTE B42_QPSK20M_Rear Face_1.5cm_Ch42190_1RB_OS50

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	164.0 x 78.0 x 11.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	BACK, 15.00	Band 42	LTE-TDD, -	3460.000, 42190	6.71	2.80	37.3

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2161	HSL3500-2025-02-23	EX3DV4 - SN3873, 2024-09-29	DAE4 Sn1389, 2024-11-11

Scan Setup

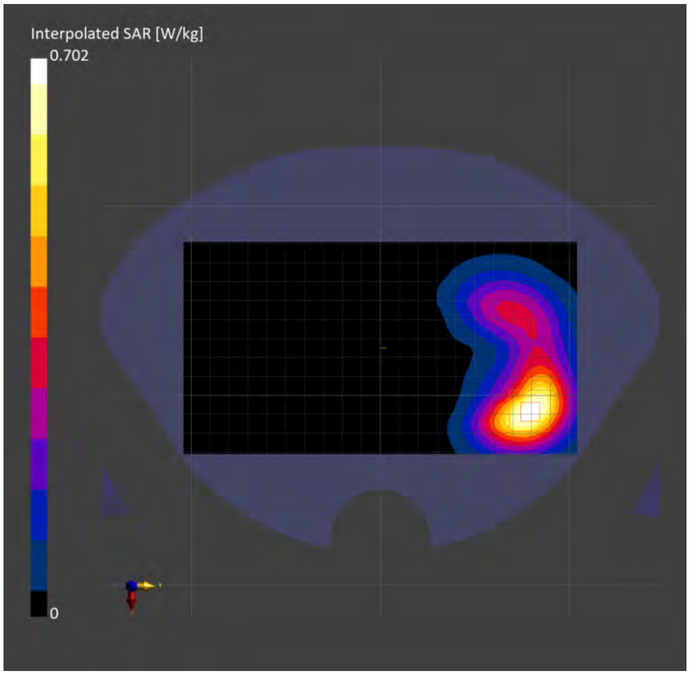
	Area Scan	Zoom Scan
Grid Extents [mm]	112.0 x 208.0	28.0 x 28.0 x 28.0
Grid Steps [mm]	8.0 x 8.0	5.0 x 5.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-02-23	2025-02-23
psSAR1g [W/kg]	0.536	0.530
psSAR10g [W/kg]	0.256	0.248
Power Drift [dB]	-0.04	-0.01
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		76.3
Dist 3dB Peak [mm]		13.5

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



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P42 LTE B48_QPSK20M_Rear Face_1.5cm_Ch55340_1RB_OS50

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	164.0 x 78.0 x 11.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	BACK, 15.00	Band 48	LTE-TDD, -	3560.000, 55340	6.71	2.89	37.1

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2161	HSL3500-2025-02-23	EX3DV4 - SN3873, 2024-09-29	DAE4 Sn1389, 2024-11-11

Scan Setup

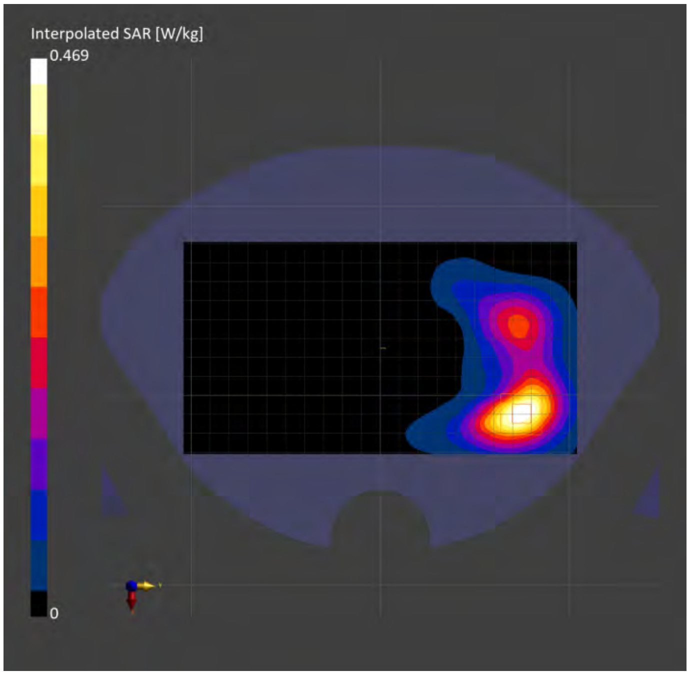
	Area Scan	Zoom Scan
Grid Extents [mm]	112.0 x 208.0	28.0 x 28.0 x 28.0
Grid Steps [mm]	8.0 x 8.0	5.0 x 5.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-02-23	2025-02-23
psSAR1g [W/kg]	0.358	0.358
psSAR10g [W/kg]	0.163	0.163
Power Drift [dB]	-0.02	-0.00
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		74.4
Dist 3dB Peak [mm]		11.2

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



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P43 LTE B66_QPSK20M_Rear Face_1.5cm_Ch132322_1RB_OS50

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	164.0 x 78.0 x 11.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	BACK, 15.00	Band 66	LTE-FDD, -	1745.000, 132322	8.31	1.40	39.3

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2161	HSL1750-2025-02-20	EX3DV4 - SN3873, 2024-09-29	DAE4 Sn1389, 2024-11-11

Scan Setup

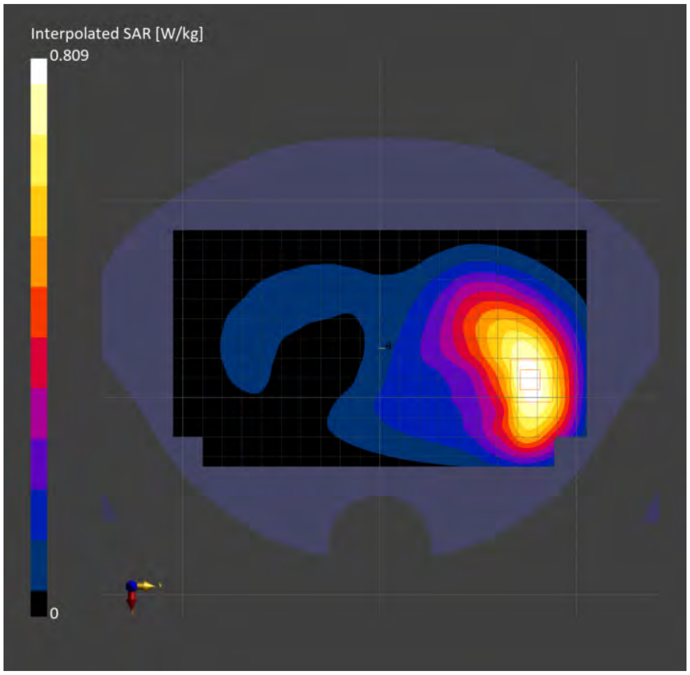
	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-02-20	2025-02-20
psSAR1g [W/kg]	0.675	0.705
psSAR10g [W/kg]	0.411	0.440
Power Drift [dB]	-0.03	-0.00
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		85.1
Dist 3dB Peak [mm]		16.1

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



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P44 FR N2_DFT-QPSK40M_Rear Face_1.5cm_Ch376000_1RB_OS1

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	164.0 x 78.0 x 11.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	BACK, 15.00	Band n2	5G NR FR1 FDD, -	1880.000, 376000	7.97	1.38	40.8

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2161	HSL1950-2025-02-21	EX3DV4 - SN3873, 2024-09-29	DAE4 Sn1389, 2024-11-11

Scan Setup

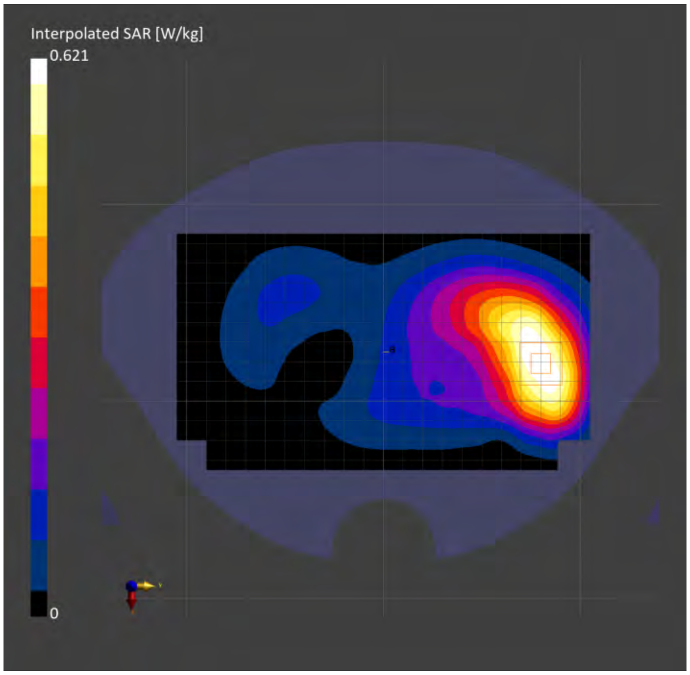
	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-02-21	2025-02-21
psSAR1g [W/kg]	0.523	0.478
psSAR10g [W/kg]	0.322	0.297
Power Drift [dB]	0.00	0.01
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		85.0
Dist 3dB Peak [mm]		16.8

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



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P45 FR N5_DFT-QPSK25M_Rear Face_1.5cm_Ch167300_1RB_OS1

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	164.0 x 78.0 x 11.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	BACK, 15.00	Band n5	5G NR FR1 FDD, -	836.500, 167300	9.47	0.942	43.3

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2161	HSL835-2025-02-18	EX3DV4 - SN3873, 2024-09-29	DAE4 Sn1389, 2024-11-11

Scan Setup

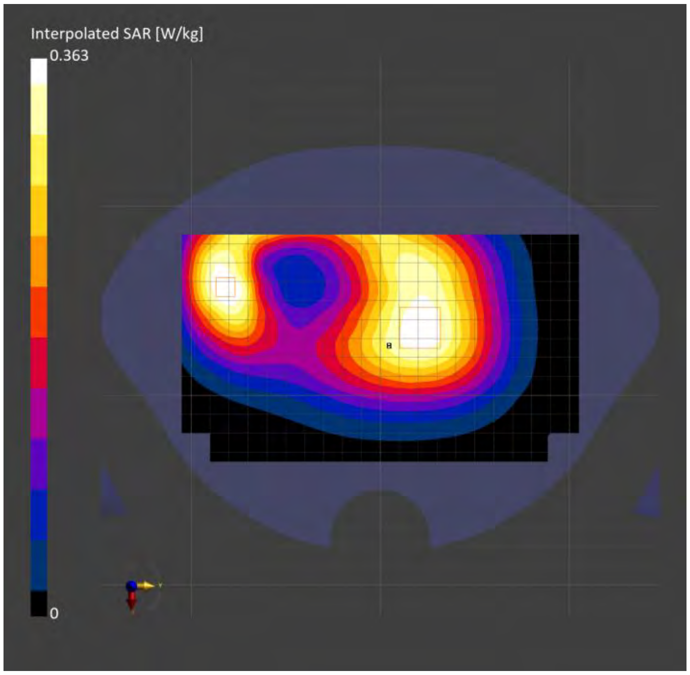
	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-02-18	2025-02-18
psSAR1g [W/kg]	0.320	0.339
psSAR10g [W/kg]	0.219	0.218
Power Drift [dB]	0.02	0.00
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		84.0
Dist 3dB Peak [mm]		16.1

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



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P46 FR N7_DFT-QPSK50M_Rear Face_1.5cm_Ch505000_1RB_OS1

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	164.0 x 78.0 x 11.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	BACK, 15.00	Band n7	5G NR FR1 FDD, -	2525.000, 505000	7.31	1.89	37.9

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2161	HSL2550-2025-02-22	EX3DV4 - SN3873, 2024-09-29	DAE4 Sn1389, 2024-11-11

Scan Setup

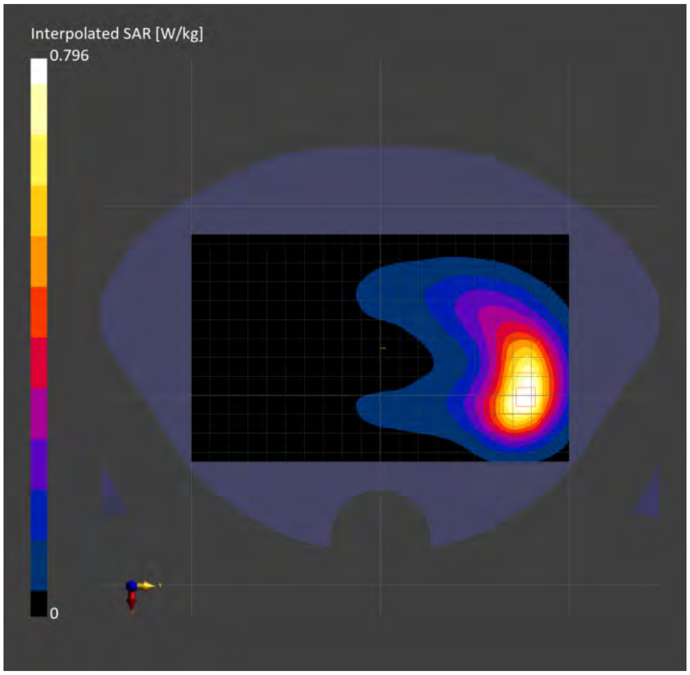
	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 200.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-02-22	2025-02-22
psSAR1g [W/kg]	0.638	0.658
psSAR10g [W/kg]	0.344	0.352
Power Drift [dB]	0.05	-0.10
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		82.0
Dist 3dB Peak [mm]		14.3

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



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P47 FR N38_DFT-QPSK40M_Rear Face_1.5cm_Ch519000_50RB_OS28

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	164.0 x 78.0 x 11.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	BACK, 15.00	Band n38	5G NR FR1 TDD, -	2595.000, 519000	7.31	1.94	37.7

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2161	HSL2550-2025-03-04	EX3DV4 - SN3873, 2024-09-29	DAE4 Sn1389, 2024-11-11

Scan Setup

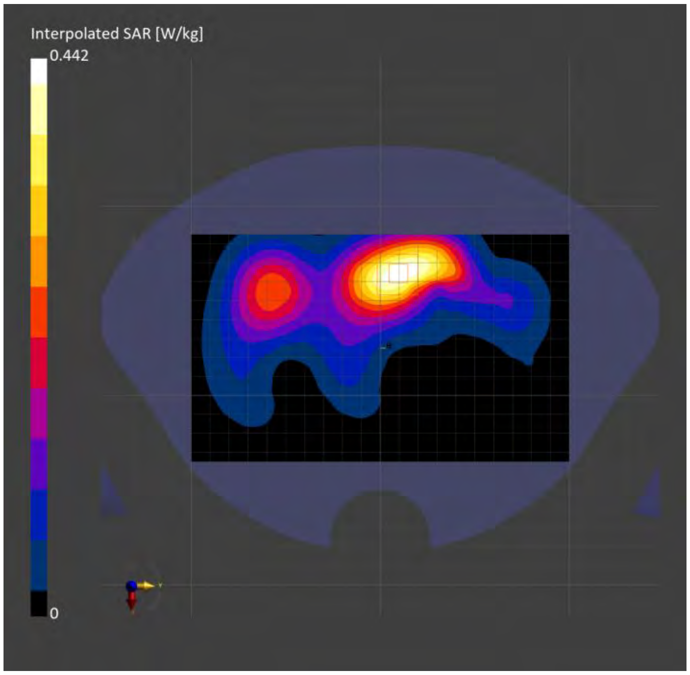
	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 200.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-03-04	2025-03-04
psSAR1g [W/kg]	0.352	0.364
psSAR10g [W/kg]	0.189	0.197
Power Drift [dB]	0.12	-0.01
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		81.1
Dist 3dB Peak [mm]		14.2

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



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P48 FR N41_DFT-QPSK100M_Rear Face_1.5cm_Ch518598_135RB_OS69

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	164.0 x 78.0 x 11.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	BACK, 15.00	Band n41	5G NR FR1 TDD, -	2592.990, 518598	7.31	1.94	37.7

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2161	HSL2550-2025-02-25	EX3DV4 - SN3873, 2024-09-29	DAE4 Sn1389, 2024-11-11

Scan Setup

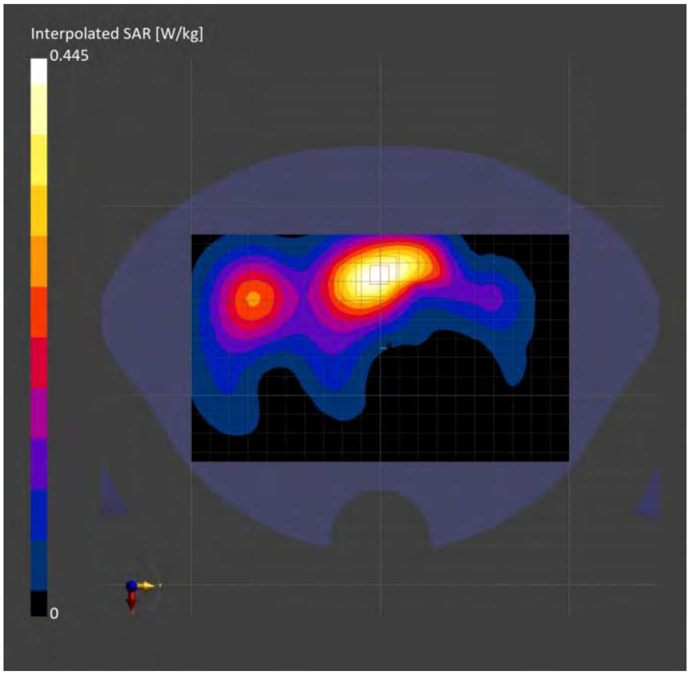
	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 200.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-02-25	2025-02-25
psSAR1g [W/kg]	0.360	0.356
psSAR10g [W/kg]	0.195	0.192
Power Drift [dB]	0.04	0.00
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		80.9
Dist 3dB Peak [mm]		15.3

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



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P49 FR N48_DFT-QPSK40M_Rear Face_1.5cm_Ch638000_1RB_OS1

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	164.0 x 78.0 x 11.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	BACK, 15.00	Band n48	5G NR FR1 TDD, -	3569.995, 638000	6.71	2.90	37.1

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2161	HSL3500-2025-02-23	EX3DV4 - SN3873, 2024-09-29	DAE4 Sn1389, 2024-11-11

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	112.0 x 208.0	28.0 x 28.0 x 28.0
Grid Steps [mm]	8.0 x 8.0	5.0 x 5.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	Y	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-02-23	2025-02-23
psSAR1g [W/kg]	0.328	0.331
psSAR10g [W/kg]	0.155	0.154
Power Drift [dB]	0.06	0.05
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		77.4
Dist 3dB Peak [mm]		13.2

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)